

EXAMINER'S AMENDMENT

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it **MUST** be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with **Aaron Waxler (Reg. # 48,027) on 10/28/2008 at 4:25 PM, EST.**

The application has been amended as follows:

Claim 5 should now read – An arrangement for interference compensation in a phase-locked loop comprising:

a voltage-controlled frequency generator, having a V_{tune} input and a VarGND terminal, wherein the VarGND terminal is connected to a controllable voltage source comprising:

a resistor connected between the VarGND terminal and a GND potential of a loop filter of said phase-locked loop; and

a controllable current source connected between the VarGND terminal and the resistor,

wherein the controllable current source is external to the phase-locked loop. –

DETAILED ACTION

Response to Arguments

Applicant's arguments, filed 8/20/2008, with respect to the rejection based on Tarusawa have been fully considered and are persuasive. The rejections based on Tarusawa have been withdrawn. In view of the newly discovered reference to **Sano (US 7,203,149)**, the above examiner's amendment was made with applicant's approval. Reasons for allowance of the amended claim are given below.

Allowable Subject Matter

Claims 5 and 7-11 are allowed.

The following is an examiner's statement of reasons for allowance:

Regarding **claim 5**, Fig. 4 of **Sano (US 7,203,149)** discloses an arrangement for interference compensation in a phase-locked loop comprising:

a voltage-controlled frequency generator [VCO 40], having a V_{tune} input [non-inverting input terminal] and a VarGND terminal [inverting input terminal], wherein the VarGND terminal is connected to a controllable voltage source comprising:

a resistor [R in block 30-2] connected between the VarGND terminal and a GND potential of a loop filter of said phase-locked loop; and

a controllable current source [current mirror comprising NM2 and NM3 in the charge pump 20, creating controllable current N1 to be fed to the resistor] connected between the VarGND terminal and the resistor.

However, neither Sano, nor any other reference of record discloses or fairly suggests, "...wherein the controllable current source is external to the phase-locked loop."

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to JAMES E. GOODLEY whose telephone number is (571)272-8598. The examiner can normally be reached on Monday-Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Robert J. Pascal can be reached on (571)272-1769. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/James E Goodley/

Examiner, Art Unit 2817

/Robert Pascal/

Supervisory Patent Examiner, Art Unit 2817